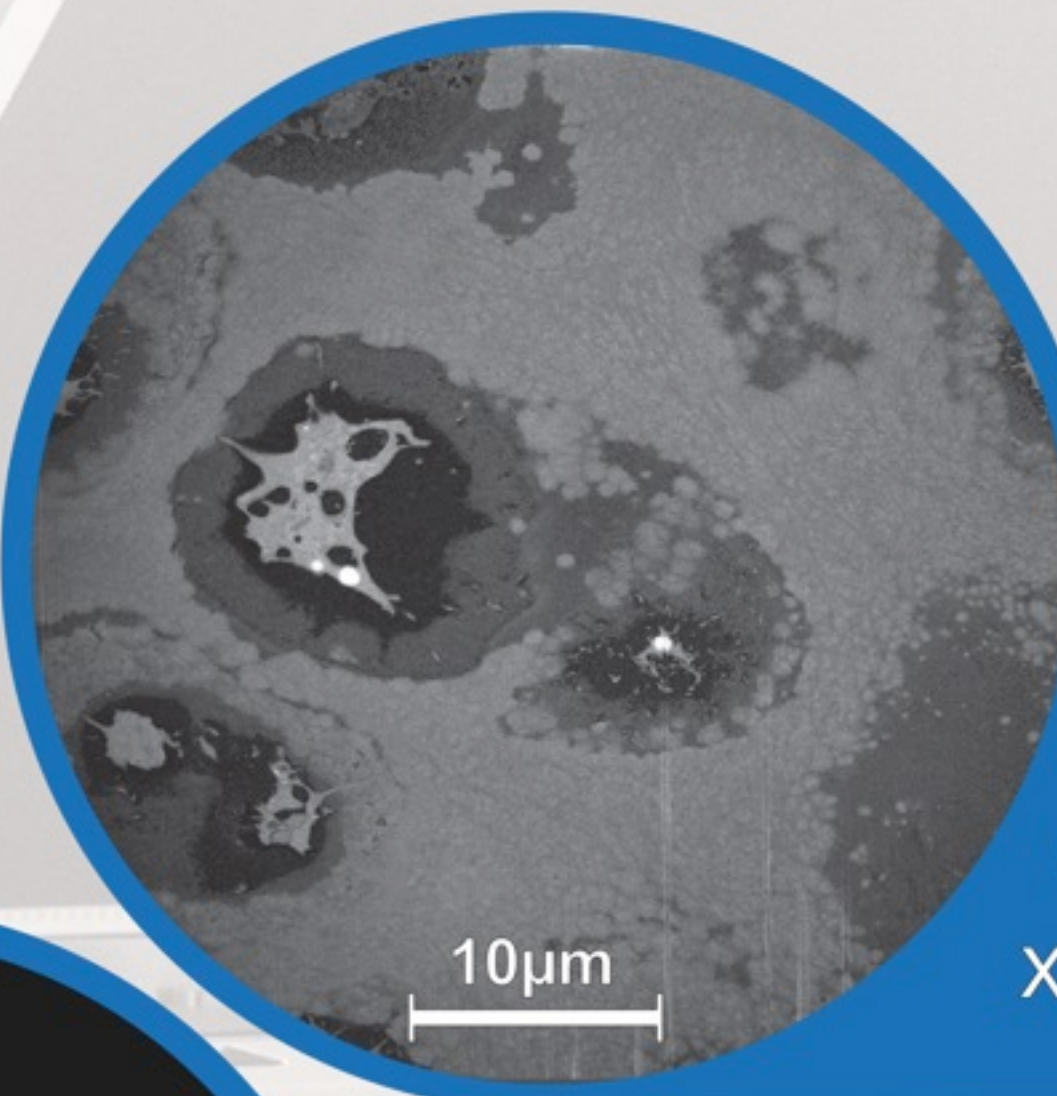


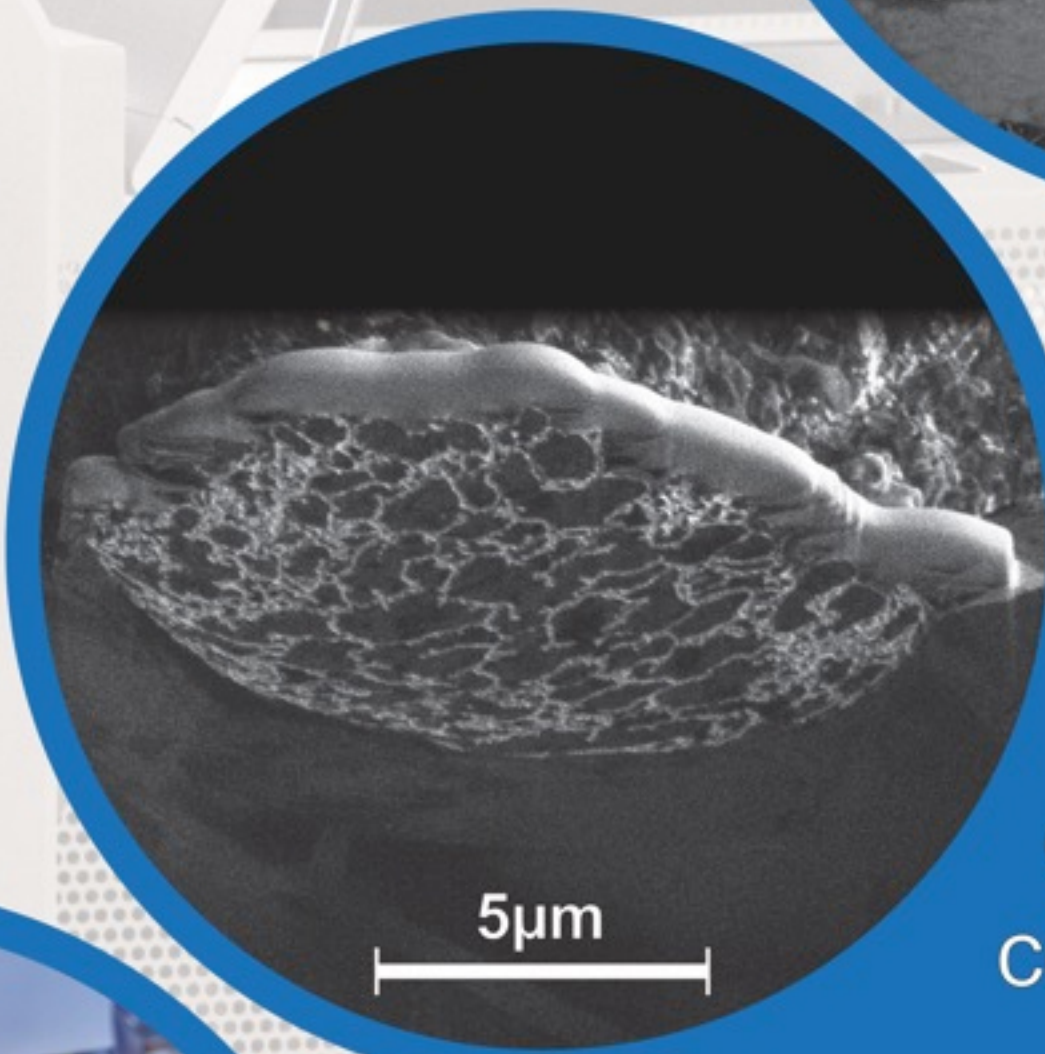
PFIB

Helios PFIB Dual Beam

- Dual beam system uses electron beam for imaging and xenon ions for imaging and precise micromachining
- Large volume 3D characterization



The 494th slice in a serial section of mouse cartilage using the xenon-ion milling.



Following cross-section milling by FIB, this secondary ion image reveals the oxides at the grain boundaries as bright contrast.



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